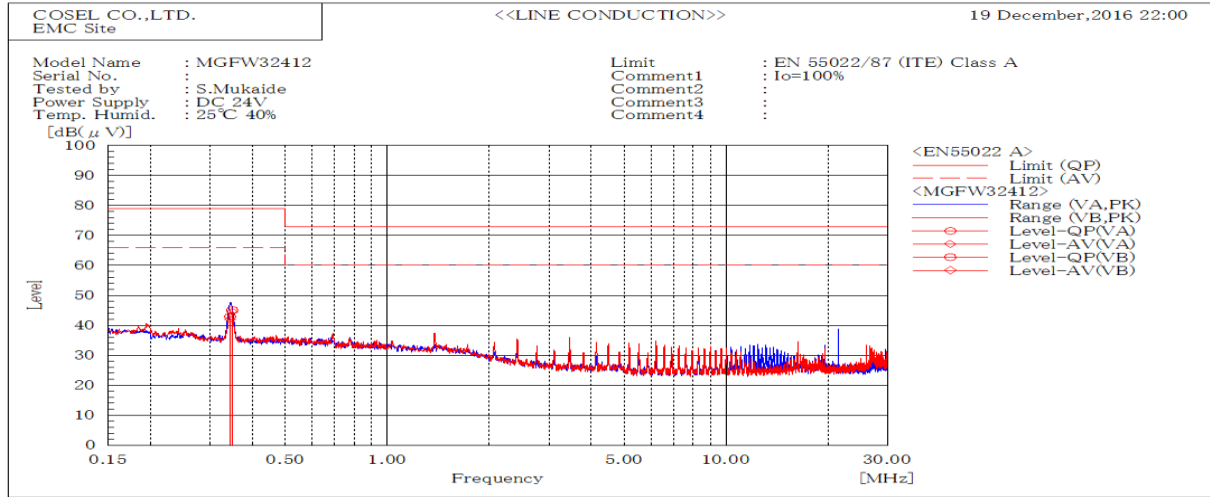
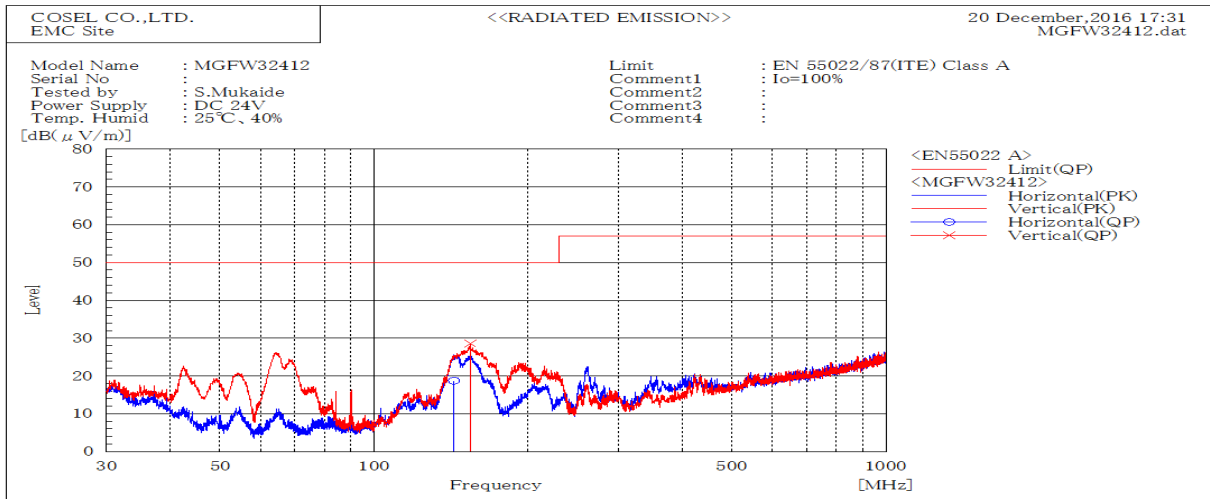


DATA SHEET		Date	06-Jan-17
Model	MGFW32412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mukaide



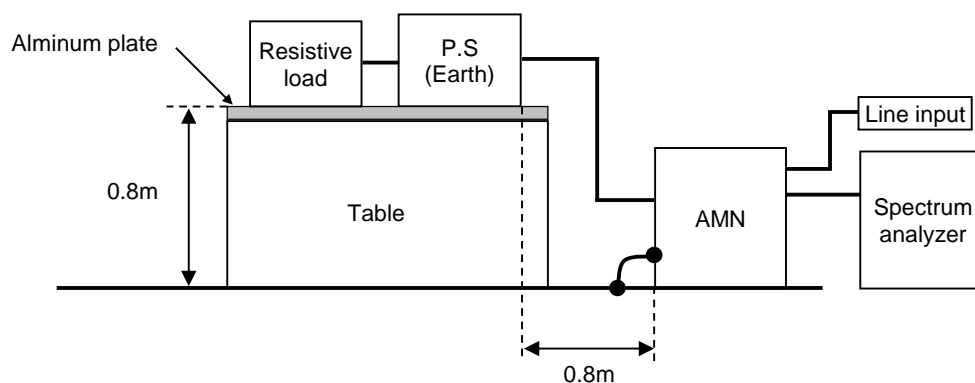
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.34336	VB	42.9	42	79	66	36.1	24	Pass	
0.34853	VA	45.1	44.5	79	66	33.9	21.5	Pass	



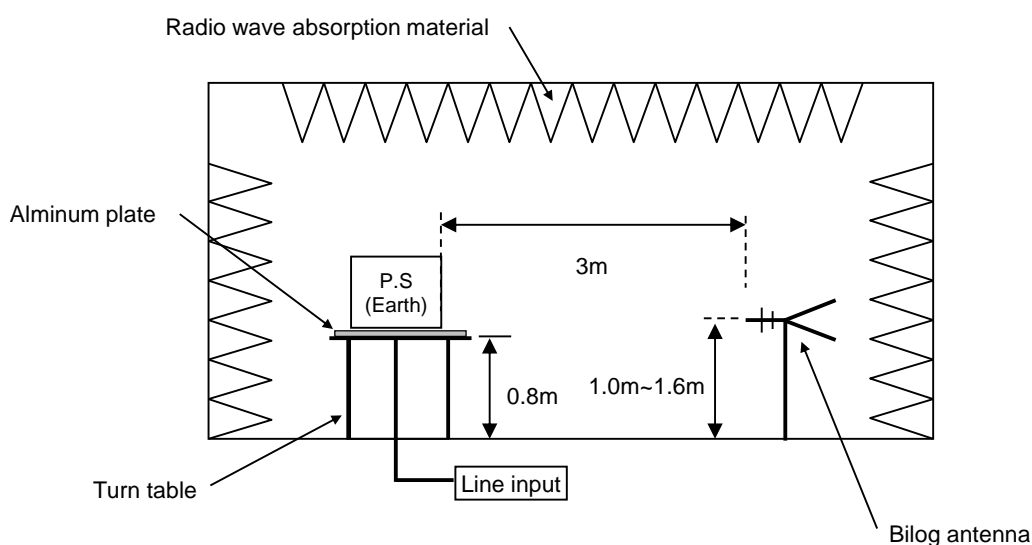
Frequency MHz	Polarization	Stability	Reading dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
143.218	H	Stable	18.8	50.0	31.2	Pass	150	241	
154.097	V	Stable	28.6	50.0	21.4	Pass	106	42	

DATA SHEET		Date	06-Jan-17
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Mukaide

1. Line conduction



2. Radiated emission

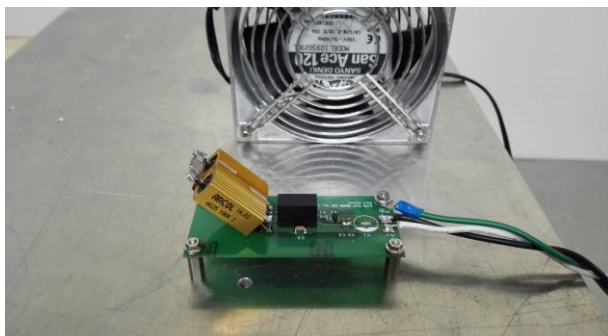


Conditions

Test : EMI
Model Name : MGFW3□□

○Photographs of Test Set-Up

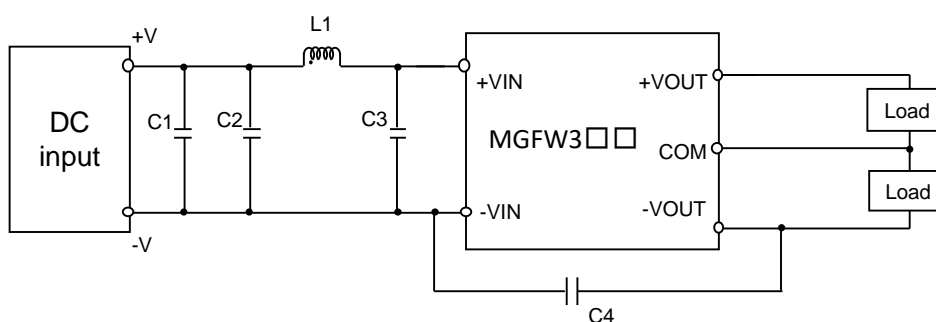
LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry



C1 :	MGFW324□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MGFW348□□	100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING)
C2 :	MGFW324□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MGFW348□□	100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING)
C3 :	MGFW324□□	50V 4.7 μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MGFW348□□	100V 2.2 μ F Ceramic capacitor (GRM31CR72A225K MURATA MANUFACTURING)
C4 :	MGFW324□□	2kV 470pF Ceramic capacitor (GR442QR73D471K MURATA MANUFACTURING)
	MGFW348□□	2kV 470pF Ceramic capacitor (GR442QR73D471K MURATA MANUFACTURING)
L1 :	MGFW324□□	900mA 10 μ H Inductor(LQH32PN100MNCL MURATA MANUFACTURING)
	MGFW348□□	550mA 22 μ H Inductor(LQH32PN220MNCL MURATA MANUFACTURING)